

RE. ISSUE

03/22/00
jc688 U.S. PTO

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Case Docket No. 2328-023 RI
Date: March 22, 2000

jc525 U.S. PTO
09/534814
03/22/00

REISSUE APPLICATION TRANSMITTAL

Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

Transmitted herewith is the reissue application of U.S. Patent No. 5,731,565 issued on March 24, 1998.

INVENTOR: Duane Charles GATES
FOR: SEGMENTED COIL FOR GENERATING PLASMA IN PLASMA PROCESSING EQUIPMENT

Enclosed are the following:

1. SPECIFICATION, CLAIMS AND DRAWINGS
 - (a) ☒ 5 pages of specification
 - ☒ 9 pages of claims
 - ☒ 1 page of abstract
 - (b) ☒ 3 sheets of formal drawings
 - ☒ No changes in the drawings upon which the original patent was issued are to be made. Therefore, in accordance with 37 CFR §1.174, please find attached, in the size required for original drawings:
 - ☒ a copy of the printed drawings of the patent
 - ☐ a photoprint of the original drawings.
 - ☒ Request for Transfer of Drawings for Reissue Application and Provision of Temporary Drawings is enclosed herewith.
2. DECLARATION AND POWER OF ATTORNEY
 - ☐ pages of declaration and power of attorney
3. PRELIMINARY AMENDMENT
 - ☐ attached
4. OFFER TO SURRENDER THE ORIGINAL LETTERS PATENT IN ACCORDANCE WITH 37 CFR §1.178
 - ☒ attached
5. LETTERS PATENT
 - ☐ original letters patent attached
 - ☐ declaration that original letters patent lost or inaccessible

09534814-032200

6. TITLE
In accordance with 37 CFR §1.171, this application for reissue is accompanied by:
☐ a certified copy of an abstract of title
or
☐ an order for an abstract of title and authorization to charge Deposit Account No. 07-1337 in the amount of \$25.00.
7. INFORMATION DISCLOSURE STATEMENT
☐ attached
8. PRIORITY - 35 USC §119
☐ Priority of Patent Application filed on in is claimed under 35 USC §119.
☐ The certified copies have been filed in prior application Serial No. filed on .
9. SMALL ENTITY STATUS (if applicable)
☐ A verified statement from the file of U.S. Patent that this filing is by a small entity is attached.
10. ASSIGNMENT INFORMATION (if applicable)
☒ The prior application is assigned of record to Lam Research Corporation, Fremont, California.
☒ Assignee's Assent to Reissue is enclosed herewith.

Respectfully submitted,

LOWE HAUPTMAN GOPSTEIN GILMAN & BERNER, LLP

Allan M. Lowe
Registration No. 19,641

by 
Michael G. Gilman
Registration No. 19,114

1700 Diagonal Road, Suite 310
Alexandria, Virginia 22314
(703) 684-1111 AML:ssw
Date: March 22, 2000

Docket No.: 2328-023 RIPATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Reissue Application of :
Duane Charles GATES :
Serial No. : Group Art Unit:
(Reissue application of :
U.S. Patent 5,731,565) : Exr:
Filed: March 22, 2000 :
For: SEGMENTED COIL FOR GENERATING PLASMA IN PLASMA PROCESSING
EQUIPMENT

ASSIGNEE'S ASSENT TO REISSUE

Assistant Commissioner for Patents
Washington, D. C. 20231

Sir:

In accordance with the provisions of 37 CFR 1.172, the undersigned Assignee of U.S. Patent 5,731,565 to Duane Charles GATES, of which it is the owner by Assignment of the entire interest, hereby assents to filing of the accompanying reissue application therefor, and further assents to filing of the reissue oath by the inventor thereof.

LAM RESEARCH CORPORATION

By: RICHARD H. LOVGRENTitle: Vice President, General Counsel
and SecretaryDate: March 22, 2000

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Docket No.: 2328-023 RIPATENT**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Reissue Application of :
Duane Charles GATES :
Serial No. : Group Art Unit:
(Reissue application of :
U.S. Patent 5,731,565) : Exr:
Filed: March 22, 2000 :
For: SEGMENTED COIL FOR GENERATING PLASMA IN PLASMA PROCESSING
EQUIPMENT

OFFER TO SURRENDER

Assistant Commissioner for Patents
Washington, D. C. 20231

Sir:

In accordance with the provisions of 37 CFR 1.178, the undersigned assignee of the accompanying reissue application for the reissue of Letters Patent Number 5,731,565 for SEGMENTED COIL FOR GENERATING PLASMA IN PLASMA PROCESSING EQUIPMENT granted on March 24, 1998, to Duane Charles Gates and assigned to Lam Research Corporation, Fremont, California, by assignment of the entire interest, hereby offers to surrender said Letters Patent.

Filed herewith is an order for a title report as required in reissue applications.

LAM RESEARCH CORPORATION

By: RICHARD H. LOVGRENTitle: Vice President, General Counsel
and SecretaryDate: March 22, 2000

BACKGROUND OF THE INVENTION

Several methods have been proposed to optimize plasma uniformity. For example, U.S. Pat. No. 4,615,755 discloses a plasma etching technique wherein uniformity of the wafer temperature is achieved by He backcooling of a wafer supported on a bowed electrode. By bowing the wafer away from the lower electrode with the cooling helium, cooling performance of the wafer is sacrificed in order to achieve

Another proposed solution for optimizing plasma uniformity is to adjust the process parameters. A problem with this proposed solution is that once process parameters are adjusted to obtain uniformity, only a small parameter range is typically available for optimizing other etch responses, such as profile.

10 Yet another proposed solution for optimizing plasma
uniformity is to modify the reactor configuration by shaping
the plasma window or by adding shrouds, spacers, or focus
rings. The disadvantage of this approach is that such mod-
15 ifications are fixed and work best in a limited parameter
range.

20 SUMMARY OF THE INVENTION

40 Preferably, each of the coil segments has an inner terminal, an outer terminal and an arcuate conductor portion having at least one turn extending between the inner and outer terminals.

The invention also provides a method of generating a transformer coupled plasma, the method comprising the steps of introducing a process gas into a plasma reaction chamber and resonating a radio frequency current in a coil comprising at least a first coil segment and a second coil segment connected in series and disposed proximate the chamber. The RF current excites the process gas into a plasma within the chamber. The method further comprises a step of varying the radio frequency current in each of the segments to improve the spatial uniformity of RF power coupling in the plasma and in turn improve the plasma and process uniformity such as etching, deposition, etc., in the reaction chamber.

The method is preferably carried out using the various a 65 coil configuration as previously mentioned. Further, the plasma can be used to process one or more substrates such as semiconductor wafers. For instance, the reaction chamber

can be sized to process a single semiconductor wafer at a time and a layer on the wafer can be etched or deposited by the plasma. During processing, the chamber is typically maintained at a wide range of pressures, such as less than 100 mTorr.

BRIEF DESCRIPTION OF THE DRAWINGS

FIG. 1 is a schematic diagram of a plasma generating device employing a conventional single winding coil;

FIG. 2 is a perspective schematic view in detail of a conventional single winding monolithic coil;

FIG. 3 is a perspective schematic view of a segmented coil configuration according to a first embodiment of the present invention;

FIG. 4 is a perspective schematic view of a segmented coil configuration according to a second embodiment of the present invention;

FIG. 5 is a perspective schematic view of a segmented coil configuration according to a third embodiment of the present invention; and

FIG. 6 is a schematic diagram of a plasma generating device employing a segmented coil according to the present invention.

DETAILED DESCRIPTION OF THE PREFERRED EMBODIMENTS

The invention relates to plasma processing of substrates, such as semiconductor wafers, flat panel displays, etc. In the case of processing such substrates, it is usually desired to provide a uniform plasma density above the exposed surface of the substrate to be processed. However, depending on the treatment to be performed on the substrate surface, non-uniform plasma density can occur above the surface. For instance, the plasma density may be greater at the substrate center than at the edge thereof or vice versa. The segmented coil of the present invention enable an adjustable RF current to be provided in each of plural segments of the TCP coil and thus achieve substantial improvement in uniformity compared to previously known coil arrangements.

The invention provides a segmented transformer coupled plasma (TCP) coil segment with at least a first coil and a second coil which, when connected to an RF source, efficiently generates a uniform plasma. Since the segmented TCP coil has multiple coil segments, variable electrical components can be connected to the individual coils, allowing RF current in each segment to be changed relative to the other segments. The current in each segment can thus be adjusted to improve the spatial uniformity of RF power deposition in the plasma and to in turn improve the plasma and etching uniformity in the plasma chamber.

FIG. 3 is a schematic drawing of a segmented TCP coil configuration according to a first embodiment of the invention. As shown in FIG. 3, the TCP coil 50 is divided into two concentric coil segments, each including an inner terminal, an outer terminal and at least one arcuate conductor portion extending between the inner and outer terminals. The two concentric coil segments are electrically connected in series with each other and are electrically connected in series to an RF source (not shown). The coil 50 includes a first inner coil segment 52 and a second outer coil segment 54. An inner tap labeled (+), and an outer tap, i.e. terminal, labeled (-) are provided to facilitate connection to the RF circuitry. An adjustable (i.e., variable) capacitor Ci is connected across the first coil 52 segment to reduce or shunt current that would otherwise flow through the first coil. This segmented

coil arrangement allows the plasma uniformity to be varied. This is done by changing the value of C_i , which varies the current through the first coil segment 52, which in turn varies the rate plasma is generated in an area in the plasma chamber beneath the coil segment 52. If the value of C_i is high, the capacitor has a low reactive impedance shunting coil 52, so less r.f. current flows through coil 52 and plasma generation in the area beneath coil 52 is reduced while coil 54 continues to generate substantially the same amount of plasma in the area below the coil 54. Conversely, if the value of C_i is low, the capacitor has a high reactive impedance shunting coil 52, so the r.f. current flowing through coil segment 52 is not appreciably reduced so both coil segments 52,54 generate plasma in the areas below them.

The capacitor C_i is not an active element in impedance matching. Further, the capacitance of the capacitor C_i is not intended to be continually adjusted, but rather, the capacitor C_i is preset to a desired value, depending upon the particular process and uniformity required for the substrate undergoing processing.

A segmented TCP coil according to a second embodiment of the invention is illustrated in FIG. 4. Referring to FIG. 4, instead of shunting the first coil segment 52 with a capacitor C_i , a switch S_1 is used to reduce or shunt the current that would otherwise flow through the first coil segment. Using the switch S_1 , there are two modes of operation. In one mode, the first coil segment 52 and the second coil segment 54 are connected in series when the switch S_1 is open and the effects are similar to the FIG. 3 embodiment when the value of C_i is low. In the second mode, the second coil segment 54 is connected in series with a shunted first coil segment 52 when the switch S_1 is closed and the effects are similar to the FIG. 3 embodiment when the value of C_i is high.

FIG. 5 is an illustration of a third embodiment of the segmented TCP coil. As shown in FIG. 5, instead of shunting the first coil segment 52, a switch S_2 is connected between the second coil segment 54 and the input to the first coil segment 52 to selectively remove the first coil segment 52 from the RF circuitry. Using the switch S_2 , there are two modes of operation. In the first mode, the first coil segment 52 and the second coil segment 54 are connected in series when the switch S_2 is closed and the effects are similar to the FIG. 3 embodiment when the value of C_i is low. In the second mode, the first coil segment 52 is disconnected from the RF circuitry and the second coil segment 54 is connected in series with the RF circuit, when the switch S_2 is open, the effect being similar to the FIG. 3 embodiment when the value of C_i is high.

The segmented TCP coil described in the embodiments above permits control of the plasma processing on different parts of the substrate undergoing treatment. For example, in plasma etching process, sufficient reduction of the center etch rate is obtained by reducing the current flowing through the first, i.e. inner coil segment. By controlling the etch rate on different parts of the wafer, a uniformly etched wafer surface can be obtained.

A plasma generating device employing the segmented TCP coil is depicted in FIG. 6. Referring to FIG. 6, the segmented TCP coil 50 includes a first coil segment 52 and a second coil segment 54. A variable electrical component V may, for example, be an adjustable capacitor C_i or a switch S_1 connected across the first coil segment 52, as shown in FIGS. 3 and 4, or a switch S_2 connected between the first coil segment 52 and the second coil segment 54, as shown in FIG. 5. The segmented coil 50 is powered by a single RF

source 30 connected via impedance matching circuitry and a tuning capacitor, as shown in FIG. 1. Alternatively, each of the coils is individually powered by different RF power sources and the coils can be arranged in non-concentric arrangements, e.g., the coils can be coplanar and arranged side-by-side in a row or pattern such as multiple rows of coils or randomly arranged coils.

The segmented TCP coil described above permits efficient generation of a spatially uniform plasma without changing the configuration of the TCP window or limiting the parameter ranges needed to optimize other processing responses. Although particular embodiments of the invention have been described, it will be appreciated by those of ordinary skill in the art that the present invention can be embodied in other specific forms without departing from the spirit or essential characteristics thereof. For example, switches and capacitors can also be provided to shunt and/or disconnect the second coil as well as the first coil and three or more coils can be utilized to form the segmented coil. Furthermore, although a TCP segmented coil with coaxially arranged first and second coils has been illustrated, the number of coils is not limited thereto, but may be any number and pattern which meets the demands of uniform plasma generation. The presently disclosed embodiments are therefore considered in all respects to be illustrative, and not restrictive. The scope of the invention is indicated by the appended claims, rather than the foregoing description, and all changes that come within the meaning and range of equivalence thereof are intended to be embraced therein.

What is claimed is:

1. An apparatus for generating plasma, the apparatus comprising:

a plasma reaction chamber having a window forming a magnetic/electrical field path into the chamber and a process gas supply for introducing process gas into the chamber;

a coil comprising at least a first coil segment and a second coil segment, the first and second coil segments being connected in series and disposed proximate an exterior surface of the window of the chamber so electromagnetic fields from said first and second coil segments are coupled through the window into the chamber;

a radio frequency source for coupling r.f. energy to the coil arrangement, the radio frequency source being effective to resonate a radio frequency current in the first and second coils; and

a power distributing component connected to one of the coil segments for controlling the flow of radio frequency current from the source through the first and second coil segments so different maximum radio frequency current amplitudes selectively flow from the source through the first and second coil segments at the same time to cause the process gas introduced into the chamber to be excited into a plasma having a relatively uniform plasma density in an area spanned by the first and second coil segments.

2. The apparatus of claim 1, wherein the power distributing component includes a circuit component connected in shunt with one of the coil segments.

3. The apparatus of claim 2, wherein the circuit component comprises an adjustable capacitor.

4. The apparatus of claim 2, wherein the circuit component comprises a switch for selectively effectively connecting one or both of the coil segments in series across a pair of excitation terminals connected to be responsive to radio frequency current derived from the radio frequency source.

5. The apparatus of claim 1, wherein the power distributing component includes a component for selectively disconnecting the first coil segment from the second coil segment so radio frequency current flows from the radio frequency source through the second coil segment but not through the first coil segment while the component disconnects the first coil segment from the second coil segment and radio frequency current flows from the radio frequency source through the first and second coil segments while the component connects the first coil segment to the second coil segment.

6. The apparatus of claim 5, wherein the component for selectively disconnecting comprises a switch.

7. The apparatus of claim 1, wherein the first and second coil segments are coplanar.

8. The apparatus of claim 1, wherein the first and second coil segments are concentrically arranged structures each including an inner terminal, an outer terminal and an arcuate conductor having at least one turn extending between the inner and outer terminals.

9. The apparatus of claim 1, wherein the first and second coil segments are powered by a single radio frequency power source, the first and second coil segments being connected to each other and the single radio frequency power source so radio frequency current flows from the radio frequency power source through a first excitation terminal of the coil connected to the first coil segment, thence through the coil to a second excitation terminal of the coil connected to the second coil segment, thence back to the source, the first and second excitation terminals being at opposite ends of the coil.

10. The apparatus of claim 1 wherein each of the coil segments includes an inner terminal, an outer terminal and an arcuate conductor portion having at least one turn extending between the inner and outer terminals, the first and second coil segments being connected in series across a pair of excitation terminals connected to be responsive to r.f. current derived from the radio frequency source.

11. The apparatus of claim 10 wherein the exterior terminal of the first coil segment is connected to the interior terminal of the second coil segment.

12. The apparatus of claim 11 wherein the component is connected across the interior and exterior terminals of the first coil segment.

13. The apparatus of claim 12 wherein the first and second coil segments are concentric with each other.

14. The apparatus of claim 11 wherein the component includes a capacitor.

15. The apparatus of claim 13 wherein the component includes a switch for selectively causing (a) the first and second coil segments to be connected in series with each other while the switch is in a first position and (b) radio frequency current from the source not to flow in the first coil segment while the switch is in a second position.

16. The apparatus of claim 12 wherein the component includes a capacitor.

17. The apparatus of claim 12 wherein the component includes a switch for selectively causing (a) the first and second coil segments to be connected in series with each other while the switch is in a first position and (b) radio frequency current from the source not to flow in the first coil segment while the switch is in a second position.

18. The apparatus of claim 4 wherein the switch and coil segments are arranged so that (a) in a first position of the switch, radio frequency current from the radio frequency source flows in series through a first of the excitation terminals, thence in series through the first and second coil

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said first and second coil segments are coupled through the window into the chamber, each of the coil segments including an inner terminal, an outer terminal and an arcuate conductor portion having at least one turn extending between the inner and outer terminals, the first coil segment being inside the second coil segment, the first and second coil segments being connected to the radio frequency source arrangement and arranged so a lower radio frequency maximum amplitude current from the source arrangement flows through the first coil segment than through the second coil segment, the radio frequency fields derived from the first and second coil segments interacting with the process gas introduced into the chamber so the process gas is excited to form a plasma having a relatively uniform plasma density in an area spanned by the first and second coil segments.

27. The apparatus of claim 20 wherein the coil arrangement for causing a lower radio frequency maximum amplitude current to flow through the first coil segment than through the second coil segment includes a relatively low non-inductive impedance shunting the first coil segment.

28. The apparatus of claim 20 wherein the source arrangement includes a single radio frequency source, the first and second coil segments being connected in series across a pair of excitation terminals responsive to radio frequency current derived from the single radio frequency source, radio frequency current from the single source flowing through one of the excitation terminals, thence through both of the first and second coil segments, thence through the other excitation terminal.

29. A method of exciting plasmas in a plasma reaction chamber supplied with a process gas, the plasmas having differing characteristics at different times but being excited so they have substantially uniform density, the process gas being excited into a plasma by a coil coupling a radio frequency electromagnetic field into the chamber, the coil having spatially disparate plural segments relative to the excited plasma, the method comprising:

during a first interval while the excited plasma has a first characteristic, effectively arranging the segments in a first way and supplying radio frequency current to the coil so the radio frequency electromagnetic field coupled by the coil to the plasma has a first spatial configuration and amplitude to cause the plasma to have a first substantially uniform density,

during a second interval while the excited plasma has a second characteristic, effectively arranging the segments in a second way and supplying radio frequency current to the coil so the radio frequency electromagnetic field coupled by the coil to the plasma has a second spatial configuration and amplitude to cause the plasma to have a second substantially uniform density, the first and second characteristics, ways, and configurations differing.

30. The method of claim 29 wherein in the first way, first and second of said segments are connected to each other and a source of radio frequency current so the same radio frequency current flows from the source to the first and second segments, and in the second way the first and second segments are connected to each other and a source of radio frequency current so different radio frequency currents flow from the source to the first and second segments.

31. The method of claim 30 wherein in the first way, the first and second segments are connected in series with each other and to the source of radio frequency current.

32. The method of claim 31 wherein in the second way the first segment is connected to the source of radio frequency

36. The method of claim 35 wherein the component 15 includes a switch, the switch when activated to the first setting connecting the first segment in series with a second of the segments so the radio frequency current flowing through the first segment flows in the second segment, the switch when activated to the second setting causing a finite 20 non-zero radio frequency current to flow from the source

through the first segment and no radio frequency current to flow from the source through the second segment.

37. The method of claim 35 wherein the component includes a non-inductive impedance connected in series with
 5 a first of the segments and shunting a second of the segments, the impedance respectively having first and second values when the component is activated to the first and second settings.

38. The method of claim 29 wherein first and second of
 10 the segments are series connected to each other and the first and second ways are respectively achieved by first and second settings of a component connected to the first segment, the component when activated to the first setting causing radio frequency current flowing through the first and
 15 second segments to have a first relation with respect to each other, the component when activated to the second setting causing radio frequency current flowing through the first and second segments to have a second relation with respect to each other.

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39. A low pressure plasma processor for treating a workpiece with a plasma comprising a low pressure chamber where the workpiece is adapted to be located, the chamber having an inlet for introducing into the chamber a gas which can be converted into the plasma for treating the workpiece, a coil positioned to couple an RF field to the gas for exciting the gas to the plasma state, the coil including interior, intermediate and peripheral portions, the interior and peripheral portions having turns connected to each other and arranged so the magnetic flux density coupled to the plasma by each of the interior and peripheral coil portions exceeds the magnetic flux density coupled to the plasma by the intermediate coil portion.

40. The processor of claim 39 wherein the interior portion includes plural radially and circumferentially extending turns, the exterior segment having at least one circumferentially extending turn, the intermediate portion being configured so it (a) does not include a complete turn, (b) is substantially less than a complete turn, and (c) includes a lead connected to ends of the turns of the interior and exterior portions.

41. The processor of claim 40 wherein the interior, intermediate and exterior portions are connected in series, the interior and exterior portions respectively including terminals for connection to a source of RF.

42. The processor of claim 40 wherein the exterior portion includes plural radially and circumferentially extending turns.

43. The processor of claim 40 wherein the interior portion includes plural spiral like turns.

44. The processor of claim 43 wherein the exterior portion includes plural spiral like turns.

5 45. A coil for use with a low pressure plasma processor for treating a workpiece with an RF plasma wherein the processor includes a low pressure chamber where the workpiece is adapted to be located, and the chamber has an inlet for introducing into the chamber a gas which can be converted into the RF plasma for treating the workpiece, the coil being adapted to be positioned to couple an RF field to the gas for exciting the gas to the plasma state, the coil comprising: interior, intermediate and peripheral portions, the interior and peripheral portions having turns connected to each other and arranged so the magnetic flux density coupled to the plasma by each of the interior and peripheral coil portions exceeds the magnetic flux density coupled to the plasma by the intermediate coil portion.

5 46. The coil of claim 45 wherein the interior portion includes plural radially and circumferentially extending turns, the exterior segment having at least one circumferentially extending turn, the intermediate portion being configured so it (a) does not include a complete turn, (b) is substantially less than a complete turn, and (c) includes a lead connected to ends of the turns of the interior and exterior portions.

47. The coil of claim 46 wherein the interior, intermediate and exterior portions are connected in series, the interior and exterior portions respectively including terminals for connection to a source of RF.

54. A low pressure plasma processor for treating a workpiece with a plasma comprising a low pressure chamber where the workpiece is adapted to be located, the chamber having an inlet for introducing into the chamber a gas which can be converted into the plasma for treating the workpiece, a coil positioned to couple an RF field to the gas for exciting the gas to the plasma state, the coil including interior, intermediate and peripheral portions, the interior portion including plural radially and circumferentially extending turns, the exterior segment having at least one circumferentially extending turn, the intermediate portion being configured so it (a) does not include a complete turn, (b) is substantially less than a complete turn, and (c) includes a lead connected to ends of the turns of the interior and exterior portions.

55. The processor of claim 54 wherein the interior, intermediate and exterior portions are connected in series, the interior and exterior portions respectively including terminals for connection to a source of RF.

56. The processor of claim 54 wherein the exterior portion includes plural radially and circumferentially extending turns.

ABSTRACT

A segmented transformer coupled plasma (TCP) coil is provided as a source for generating a uniform plasma in a plasma reactor. The segmented TCP is divided into two or more segment coils which, when connected to an RF source, produces a circulating flow of electrons to cause a magnetic field in the plasma. Because the segmented TCP employs multiple segment coils, a plasma is generated that is more spatially uniform than the plasma produced by a monolithic coil. This is implemented using a power distributing component that allows the RF current to be distributed in the segment coils such that a uniform plasma density can be obtained in an area spanned by the coils. For instance, variable shunts, switchable shunts, and disconnect switches can be used to vary the RF currents in the individual coils.

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Reissue Application of :
Duane Charles GATES :
Serial No. : Group Art Unit:
(Reissue application of :
U.S. Patent 5,731,565) : Exr:
Filed: March 22, 2000 :
For: SEGMENTED COIL FOR GENERATING PLASMA IN PLASMA PROCESSING
EQUIPMENT

REQUEST FOR TRANSFER OF DRAWINGS FOR REISSUE APPLICATION
AND PROVISION OF TEMPORARY DRAWINGS

Assistant Commissioner for Patents
Washington, D. C. 20231

Sir:

In accordance with the provisions of 37 CFR 1.174, applicants courteously request that the drawings of applicant's patent, U.S. Patent 5,731,565, filed July 27, 1995, be transferred to the present Reissue Application. Temporarily, applicant provides herewith three (3) sheets of copies of drawings from the original patent for the subject reissue application.

Respectfully submitted,

LOWE HAUPTMAN GOPSTEIN GILMAN & BERNER, LLP

Allan M. Lowe
Registration No. 19,641

by: 
Michael G. Gilman
Registration No. 19,114

1700 Diagonal Road, Suite 310
Alexandria, Virginia 22314
(703) 684-1111/FAX: (703) 518-5499
AML:ssw
Date: March 20, 2000

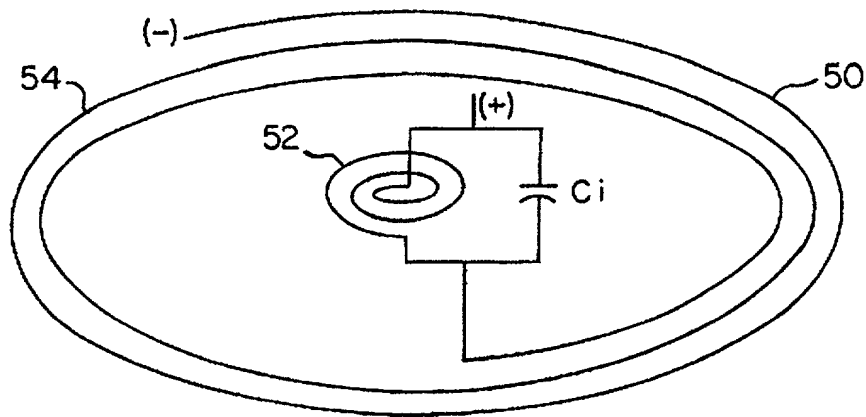


Figure 3

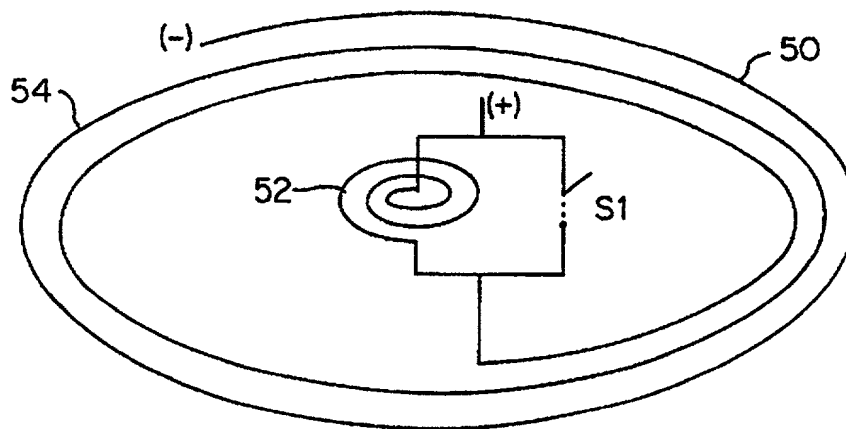


Figure 4

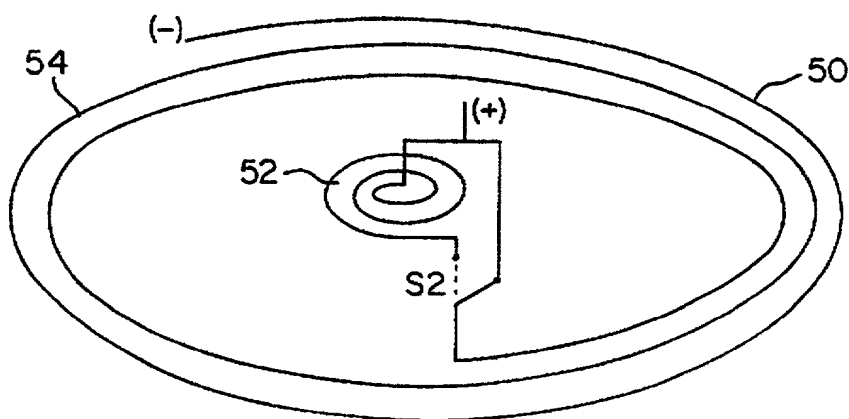


Figure 5

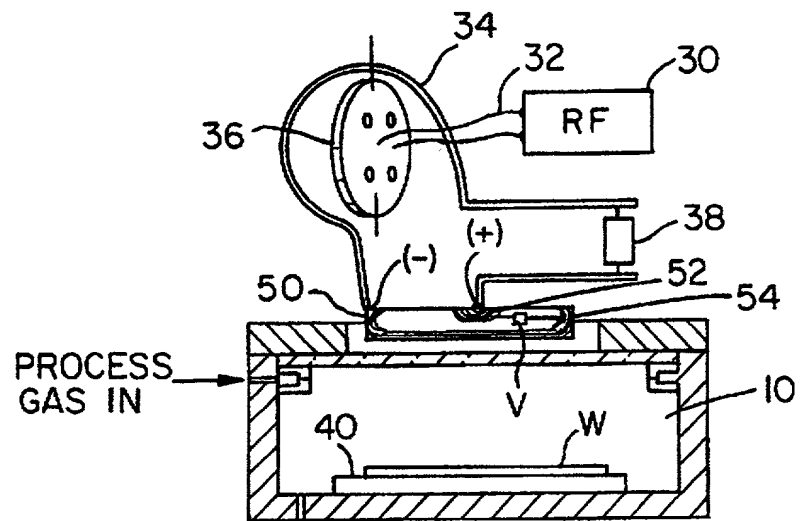


Figure 6

#3





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Group Art Unit: 3742

Examiner:

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Parameter	Value	Unit
Temperature	25.0	°C
Pressure	1.013	bar
Humidity	50.0	%
Flow rate	1.0	L/min
Concentration	0.1	g/L
pH	7.0	
Viscosity	0.01	P
Surface tension	0.02	N/m
Electrical conductivity	0.1	μS/cm
Optical density	0.1	
Refractive index	1.33	
Dielectric constant	1.0	
Magnetic permeability	1.0	
Thermal conductivity	0.1	W/mK
Specific heat capacity	1.0	J/gK
Thermal expansion coefficient	0.01	1/K
Compressibility	0.01	1/Pa
Acoustic impedance	0.1	kg/m ² s
Speed of sound	340	m/s
Wavelength	0.1	m
Frequency	1.0	Hz
Power	0.1	W
Energy	0.1	J
Force	0.1	N
Moment	0.1	Nm
Stress	0.1	Pa
Strain	0.1	
Modulus	0.1	Pa
Poisson's ratio	0.1	
Yield strength	0.1	Pa
Tensile strength	0.1	Pa
Elongation at break	0.1	%
Impact strength	0.1	J/m ²
Hardness	0.1	Pa
Friction coefficient	0.1	
Wear rate	0.1	m ³ /N
Corrosion rate	0.1	mm/a
Galvanic potential	0.1	V
Electrode potential	0.1	V
Open circuit potential	0.1	V
Polarization resistance	0.1	Ω
Charge transfer resistance	0.1	Ω
Double layer capacitance	0.1	F
Warburg impedance	0.1	Ω
Diffusion coefficient	0.1	m ² /s
Permeability coefficient	0.1	m ² /s
Sorption coefficient	0.1	
Diffusion time	0.1	s
Permeation rate	0.1	m ³ /m ² s
Flux	0.1	m ³ /m ² s
Concentration gradient	0.1	mol/m ³
Temperature gradient	0.1	°C/m
Pressure gradient	0.1	Pa/m
Velocity	0.1	m/s
Acceleration	0.1	m/s ²
Angular velocity	0.1	rad/s
Angular acceleration	0.1	rad/s ²
Moment of inertia	0.1	kgm ²
Rotational speed	0.1	rpm
Torque	0.1	Nm
Power	0.1	W
Efficiency	0.1	%
Loss	0.1	W
Heat flux	0.1	W/m ²
Temperature difference	0.1	°C
Area	0.1	m ²
Volume	0.1	m ³
Mass	0.1	kg
Weight	0.1	N
Force	0.1	N
Pressure	0.1	Pa
Stress	0.1	Pa
Strain	0.1	
Modulus	0.1	Pa
Poisson's ratio	0.1	
Yield strength	0.1	Pa
Tensile strength	0.1	Pa
Elongation at break	0.1	%
Impact strength	0.1	J/m ²
Hardness	0.1	Pa
Friction coefficient	0.1	
Wear rate	0.1	m ³ /N
Corrosion rate	0.1	mm/a
Galvanic potential	0.1	V
Electrode potential	0.1	V
Open circuit potential	0.1	V
Polarization resistance	0.1	Ω
Charge transfer resistance	0.1	Ω
Double layer capacitance	0.1	F
Warburg impedance	0.1	Ω
Diffusion coefficient	0.1	m ² /s
Permeability coefficient	0.1	m ² /s
Sorption coefficient	0.1	
Diffusion time	0.1	s
Permeation rate	0.1	m ³ /m ² s
Flux	0.1	m ³ /m ² s
Concentration gradient	0.1	mol/m ³
Temperature gradient	0.1	°C/m
Pressure gradient	0.1	Pa/m
Velocity	0.1	m/s
Acceleration	0.1	m/s ²
Angular velocity	0.1	rad/s
Angular acceleration	0.1	rad/s ²
Moment of inertia	0.1	kgm ²
Rotational speed	0.1	rpm
Torque	0.1	Nm
Power	0.1	W
Efficiency	0.1	%
Loss	0.1	W
Heat flux	0.1	W/m ²
Temperature difference	0.1	°C
Area	0.1	m ²
Volume	0.1	m ³
Mass	0.1	kg
Weight	0.1	N
Force	0.1	N
Pressure	0.1	Pa
Stress	0.1	Pa
Strain	0.1	
Modulus	0.1	Pa
Poisson's ratio	0.1	
Yield strength	0.1	Pa
Tensile strength	0.1	Pa
Elongation at break</		

Sir:

As a below-named inventor, I hereby declare that:

My residence, post office address, and citizenship are as stated below next to my name; and
that

I verily believe that I am the original and first inventor of the invention entitled SEGMENTED COIL FOR GENERATING PLASMA IN PLASMA PROCESSING EQUIPMENT, described and claimed in the Reissue Application filed March 22, 2000; that I understand the content of the specification filed therein; that I have reviewed and understand the content of the specification including the claims, as well as the claims referred to in this Declaration; that I do not

know and do not believe the same was ever known or used in the United States of America before my invention thereof, or patented or described in any printed publication in any country before my invention thereof or more than one year prior to July 27, 1995; that the same was not in public use or on sale in the United States of America more than one year prior to July 27, 1995; that the invention has not been patented or made the subject of an inventor's certificate issued before July 27, 1995, in any country foreign to the United States of America on an application filed by me or my legal representatives or assigns more than twelve months prior July 27, 1995; that I acknowledge my duty to disclose information of which I am aware which is material to the examination of this application; and that no application for patent or inventor's certificate on this invention has been filed in any country foreign to the United States of America prior to the original application Serial No. 08/507,971 by me or my legal representatives or assigns. My original U.S. Patent 5,731,565, issued March 24, 1998, which matured from Serial No. 08/507,971 filed July 27, 1995, is believed to be wholly or partly inoperative because I claimed less than I had a right to claim through error and without any deceptive intention. Every error in the patent which was corrected in the present reissue application, and is not covered by a prior oath/declaration submitted in this application, arose without any deceptive intention on the part of the applicants.

The errors include the following:

1. The failure to claim the subject matter of claims 39–56 of the Reissue Application. In particular, the failure to include a claim of the scope defined by independent claim 39, upon which claims 40–44 depend, that the interior and peripheral coil portions have turns connected to each and arranged so the magnet flux density coupled to the plasma by the interior and peripheral coil portions exceeds the magnetic flux coupled to the plasma by the intermediate coil portion.

2. The error also includes the failure to include a claim of the scope defined by independent claim 45, upon which claims 46–50 depend, that the intermediate and peripheral portions of the coil have turns connected to each other and arranged so the magnetic flux density coupled to the plasma by each of the interior and peripheral coil portions exceeds the magnetic flux density coupled to the plasma by an intermediate coil portion.

3. The error also includes the failure to include a claim of the scope defined by independent claim 51, upon which claims 52 and 53 depend, that the interior coil portion include (1) plural radially and circumferentially extending turns, (2) an exterior coil portion having at least one circumferentially extending turn, and (3) an intermediate coil portion configured so it (a) does not include a complete turn, (b) is substantially less than a complete turn, and (c) includes a lead connected to ends of the interior and exterior portions.

4. The error also includes the failure to include a claim of the scope defined by independent claim 54, upon which claims 55 and 56 depend, that an intermediate coil portion be configured so (1) it does not include a complete turn, (2) is substantially less than a complete turn, and (3) includes a lead connected to the ends of the turns of the interior and exterior portions.

5. The error also includes the failure to include the foregoing features of the independent claims in various combinations. For example, claim 40 requires the interior coil portion to include radially and circumferentially extending turns, and the exterior segments to have at least one circumferentially extending turn. The intermediate portion is configured so it (a) does not include a complete turn, (b) is substantially less than a complete turn, and (c) includes a lead connected to ends of the turns of the interior and exterior portions. Similar limitations to those set forth in claim 40 are set forth in claim 46, which depends on claim 45.

6. The error also includes the failure to include claims of the scope defined in dependent claims 41, 47, 52 and 55 with the requirements for the interior, intermediate and exterior coil portions to be connected in series, with the exterior and interior portions respectively including terminals for connection to a source of RF.

7. I first became aware of these errors when my attorney reviewed the entire '565 patent for reissue purposes. On information and belief, my attorney became aware of the error when my '565 patent was cited as an anticipatory reference against a pending application owned by my assignee, Lam Research Corporation. The Office Action included a rejection that all features of claims 1-3, 5 and 16 of U.S. Patent Application Serial No. 08/931,503 were found in my '565 patent. The Office Action was mailed by the U.S. Patent and Trademark Office, on November 15, 1999, and received by my attorney on November 16, 1999. My attorney realized that the features of claim 1-3, 5-13 and 16 of the '503 application were included in my '565 patent. My attorney realized that the coverage of the '503 application should have been incorporated in the claims of my '565 patent and received authorization from the Legal Department of Lam Research Corporation to prepare a Reissue Application with appropriate claims to obtain the broader coverage.

I hereby appoint the following attorneys to prosecute this application and to transact all business in the Patent and Trademark Office connected therewith:

Allan M. Lowe, Reg. No. 19,641; Israel Gopstein, Reg. No. 27,333; Benjamin J. Hauptman, Reg. No. 29,310; Kenneth M. Berner, Reg. No. 37,093; Michael G. Gilman, Reg. No. 19,114 and Randy A. Noranbrock, Reg. No. 42,940, all of Lowe Hauptman Gopstein Gilman & Berner, LLP; and Jeffrey J. Brooks, Reg. No. 35,834 and Marilyn Glaubenslee, Reg. No. 35,521, both of Lam Research Corporation.

Serial No. 09/534,814

All future correspondence connected therewith should be addressed to the following
address:

Allan M. Lowe
LOWE HAUPTMAN GOPSTEIN GILMAN & BERNER, LLP
1700 Diagonal Road, Suite 310
Alexandria, Virginia 22314-2848

I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.

Full name of sole inventor: Duane Charles GATES

Inventor's signature: Duane Charles Gates Date: July 3, 2000

Residence: Danville, CA 94526

Citizenship: U.S.A.

Post Office Address: 94 Stowbridge Court, Danville, CA 94526